

EPA ENERGY STAR®
Lighting Webinar Series
The Quest for a Short Term Reliability Test
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A short-duration LED system life test

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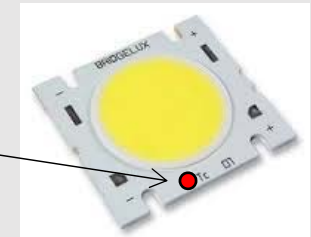
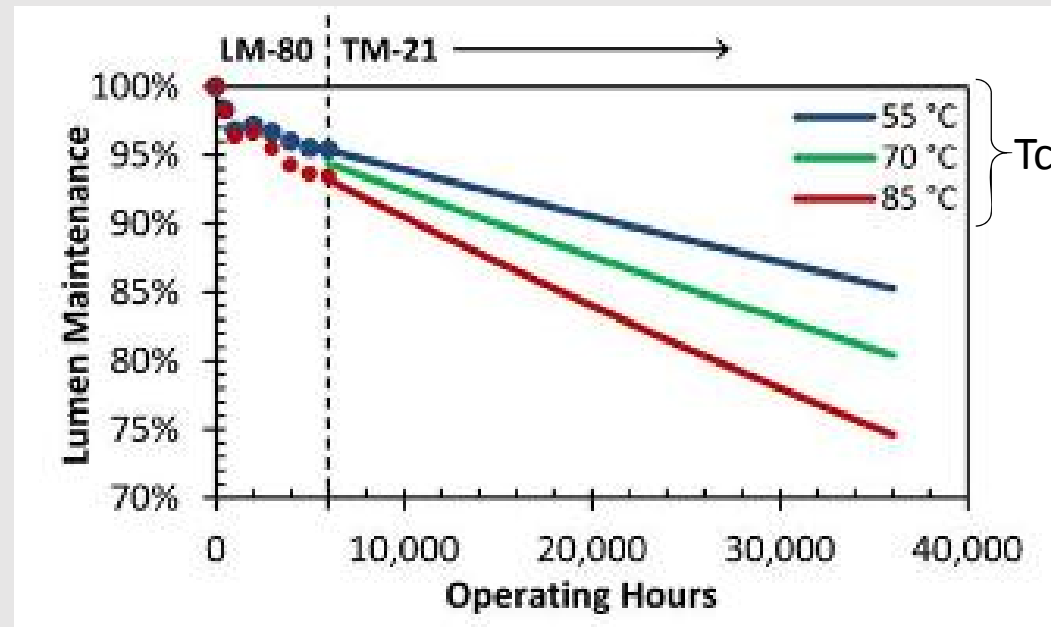
Background

- One of the claimed benefits for LED lighting is long life.
 - Lifetime claims for commercially available products are typically in the 25,000-hour range.
- User expectation:
 - The lamp will last 25,000 hours in all applications.



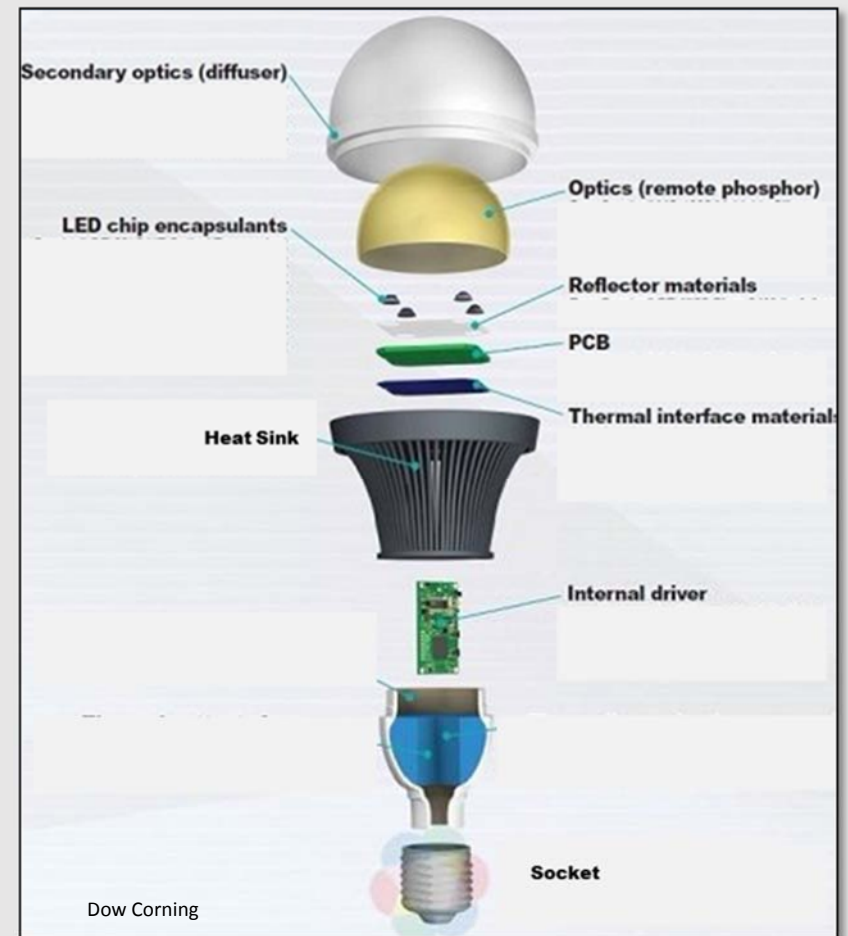
Background

- How is LED system life estimated today?
 - The LED in the system is tested according to IESNA LM-80 and the L70 value is estimated according to IESNA TM-21.



Background

- An LED system has many components
 - LED(s), circuit board, driver, optics, heat sink, and others
- Failure of any one component can cause system failure
- Failure can be catastrophic or parametric



Background

- Lighting system use pattern in applications:
 - Office:
 - 7 am to 7 pm
(12 hrs on, 12 hrs off)
 - Home:
 - 5 am to 9 am and
 - 6 pm to 10 pm
(4 hrs on, 4 hrs off)



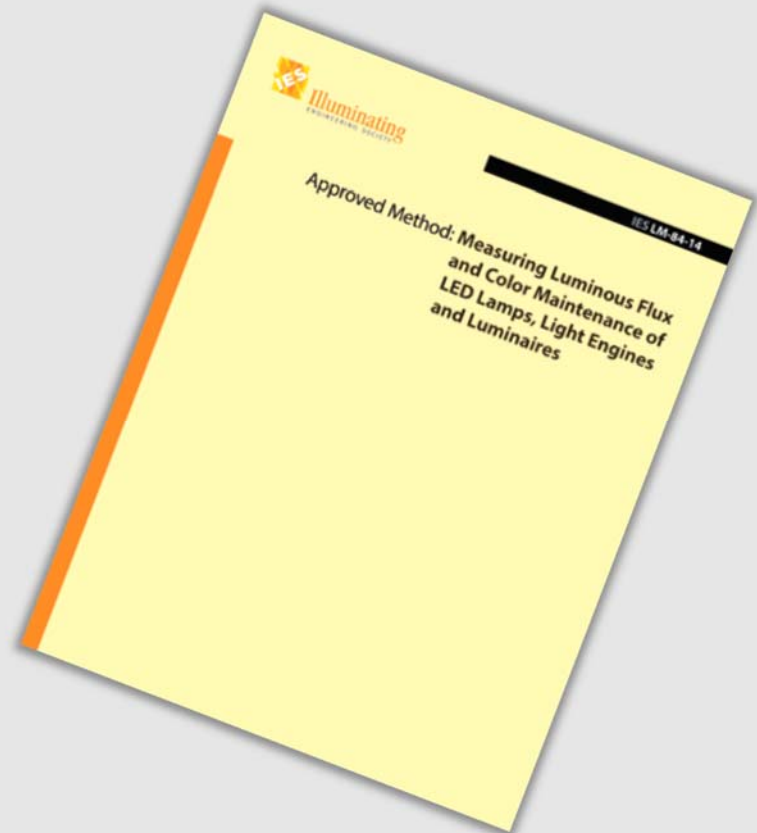
<https://community.lighting.philips.com/>



<http://www.ledsource.com/products/residential>

Background

- For testing LED systems, the IESNA published a method, LM-84-14.
 - This is an improvement over LM-80 because it tests the whole system rather than just the LED.
- However, the drawbacks are:
 - Continuous-on testing
 - Considers only parametric failure of system light output (lumen depreciation) and color maintenance



Background

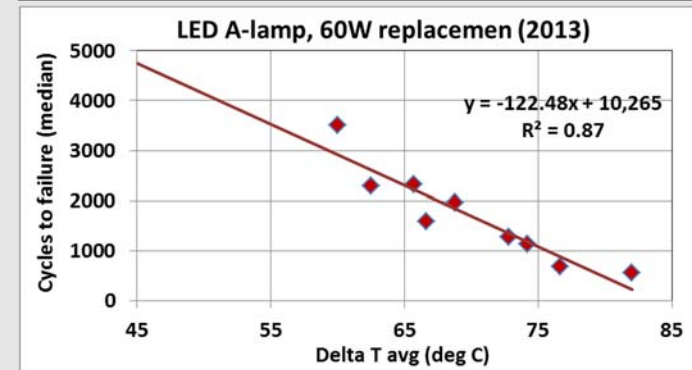
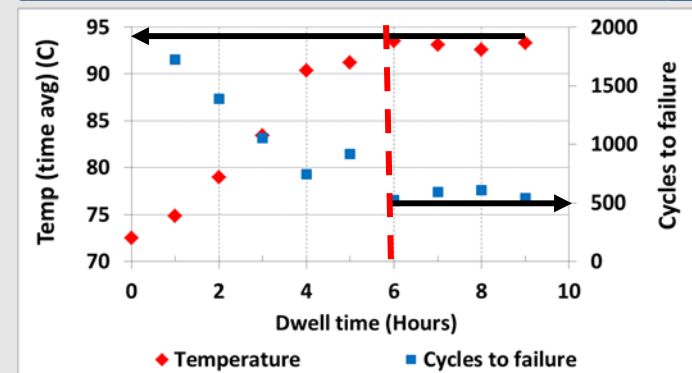
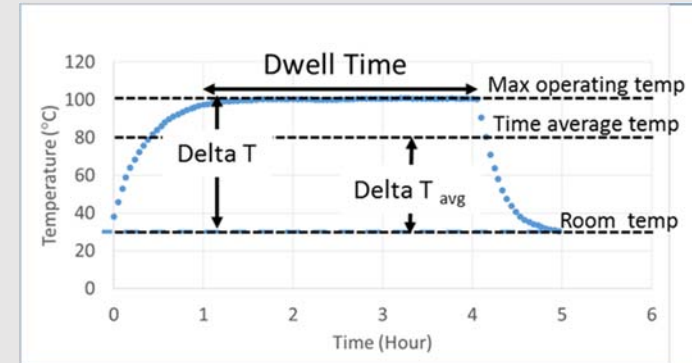
- Since 2009, LRC researchers have been investigating LED system life testing
 - Sponsored by the ASSIST program
- **Study objective:** To develop a short-duration test method that can be useful for estimating LED system life when used in applications.

ASSIST program sponsors



Background

- LRC initial study findings:
To accurately capture system failure and estimate life,
 - The whole lighting system must be tested
 - The test procedure must include on-off cycling
 - Suitable delta T and dwell time
 - Longer dwell time results in shorter time to failure
- Results: Catastrophic failure
 - A good linear relationship between cycles to failure and delta temperature



Background – Public presentations

- The test procedure and the results of this initial LRC study were presented at several venues to gather feedback
 - 2014
 - Accelerated Life-testing Study to Predict LED System Failure
 - Strategies in Light, Feb 25-27, 2014, Santa Clara, CA
 - An Accelerated Test Method for Estimating LED System Life
 - The 14th International Symposium on the Science and Technology of Lighting (LS14), June 22-27, 2014, Como, Italy
 - LED System Life
 - 9th SSL Annex, Expert Meeting, October 2014, Portland, OR
 - 2015
 - LED Life versus LED System Life
 - In: SID '15 Digest of Technical Papers, paper 62-2, SID Display Week 2015: International Symposium, Seminar and Exhibition, May 31-June 5, 2015, San Jose, CA

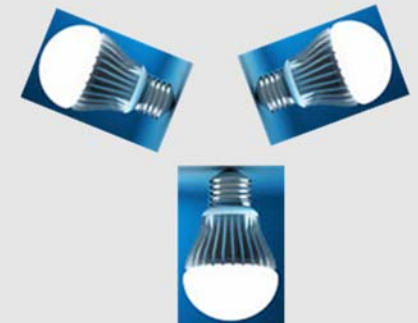
Expanded study

- With additional funding from BPA, NYSERDA and ASSIST the LRC expanded the study
 - Larger sample size and more systems
 - Study objective: To develop a test method that can help estimate LED system life based on factors such as
 - environment temperature (resulting T_j)
 - use pattern (On-Off cycling)
- and
- considers both catastrophic and parametric failure times
 - Uses the shorter of the two



Pilot study: Identify LED T_j in application

- An LED A-lamp, 75W incandescent equivalent, in a 3-lamp surface mount fixture
 - T_j of LEDs = 146°C
 - T_{room} = 30°C
 - DT = 116°C
 - DT = T_j - T_{room}
- Two other LED A-lamps, 60W incandescent equivalent, in a 3-lamp surface mount fixture
 - Delta Temperature = 90°C
 - Delta Temperature = 85°C



Experiment setup and test procedure

- Type of product tested

- LED A-lamps
- 90 samples

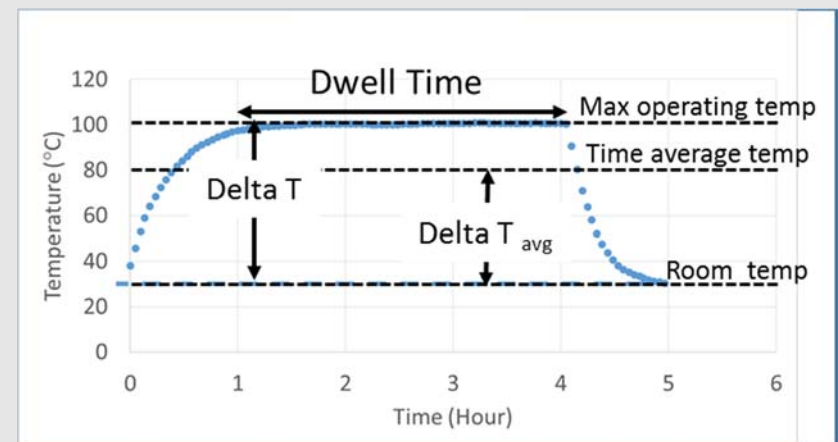
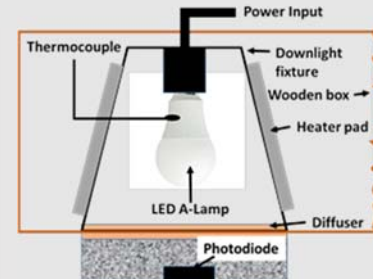


- Independent variables

- Delta Temperature (ΔT)
 - D80/D90/D100 °C
 - Based on pilot study results
- Dwell Time
 - 2-hrs/4-hrs/Continuous

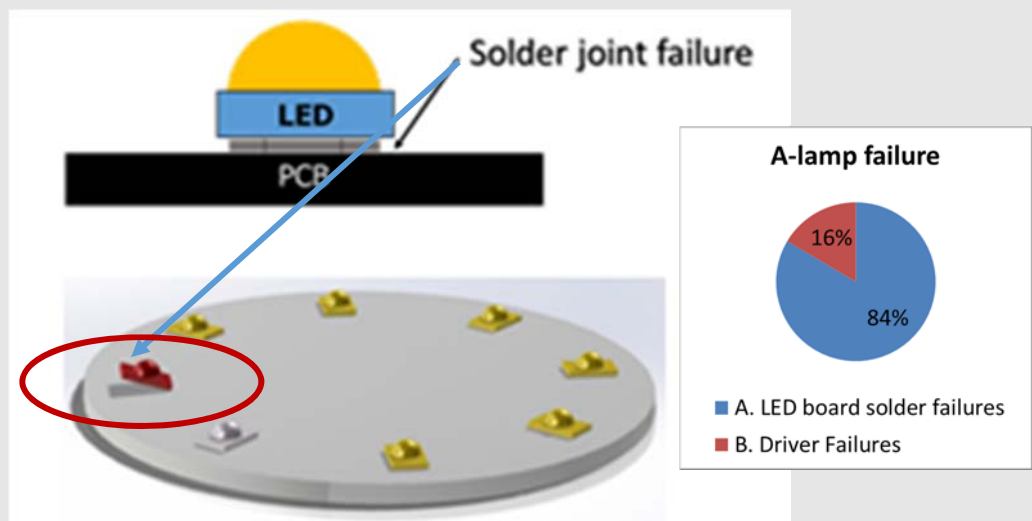
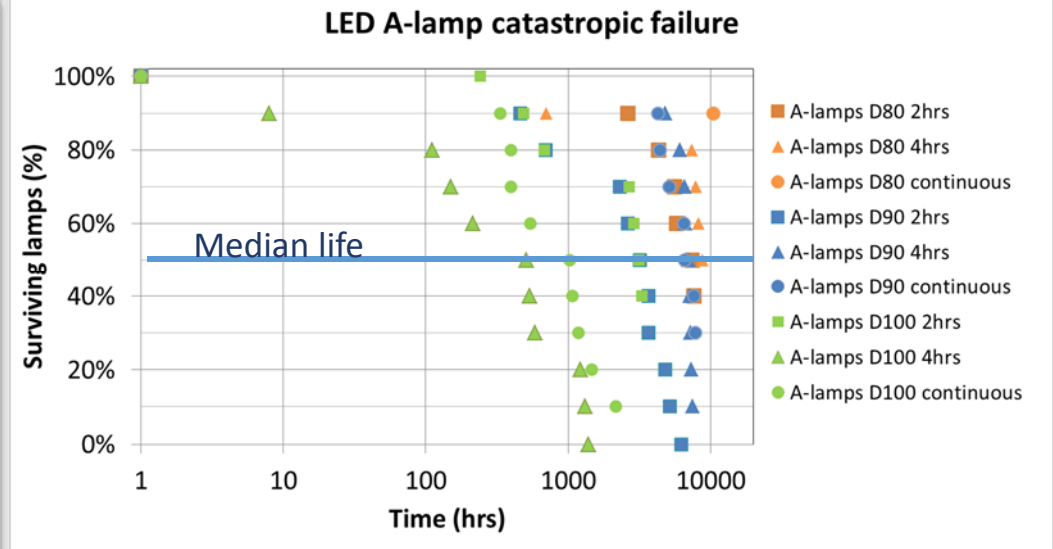
- Dependent variables

- Light output
- Chromaticity
- Power Input
- Current Input
- Lamp temperature



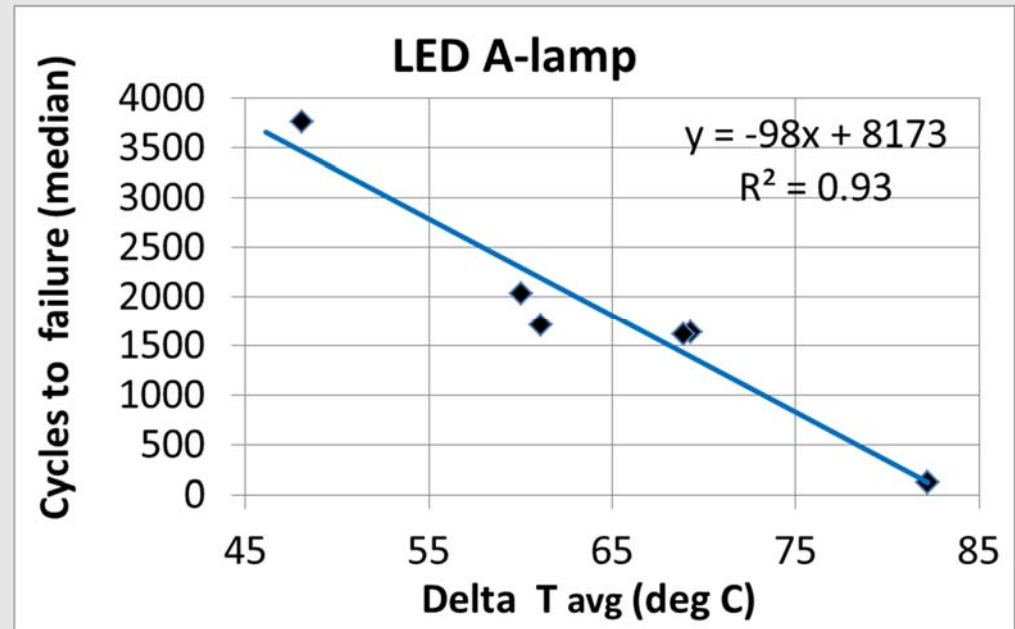
Data: LED A-lamp catastrophic failures

- Median life due to catastrophic failure is affected by delta T and dwell time
- Failure modes
 - LED failure = 84%
 - PCB solder failure
 - Driver failure = 16%



Data: LED A-lamp catastrophic failures

- Delta temperature:
 - Higher delta T results in shorter time to failure
- Dwell time:
 - Shorter dwell time results in shorter time to failure
 - For 80°C and 90°C
 - The trend is not clear at 100°C
 - Possible other failure mechanisms
- Cycles to failure as a function of delta temperature shows an inverse linear relationship
 - Goodness-of-fit (R^2) > 0.9



Delta T average
(°C)

Delta T	Dwell time	
	2 hrs	4 hrs
80°C	48°C	60°C
90 °C	61°C	69°C
100°C	69°C	82°C

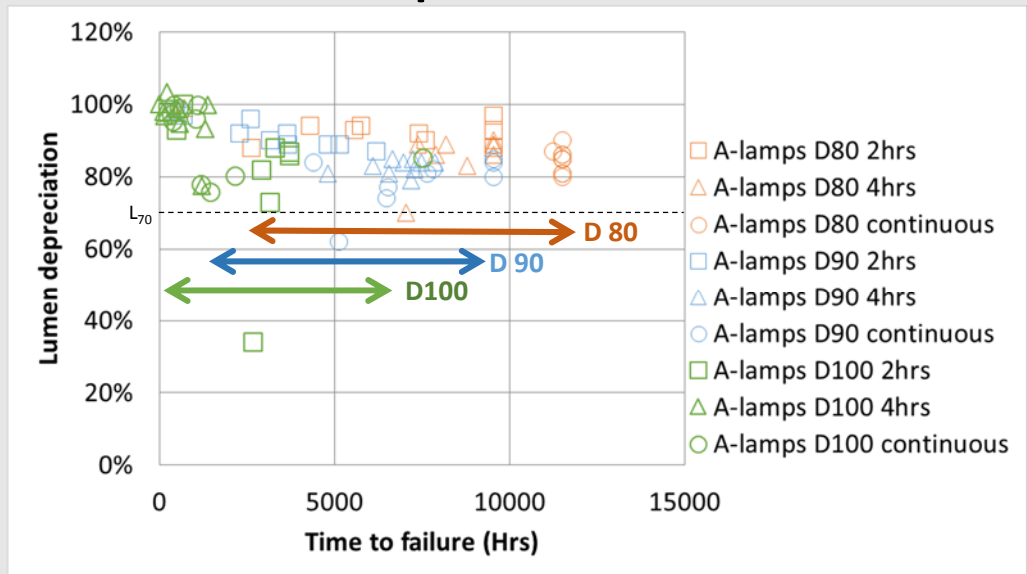
Time to failure
(median life in hours)

Delta T	Dwell time	
	2 hrs	4 hrs
80°C	7,516	8,801
90 °C	3,411	7,091
100°C	3,225	521

Data: LED A-lamp lumen depreciation

- The majority of the LED A-lamps tested failed catastrophically before the lumen depreciation reached the 70% value.

Lumen depreciation at failure



Results: A-lamp lumen depreciation

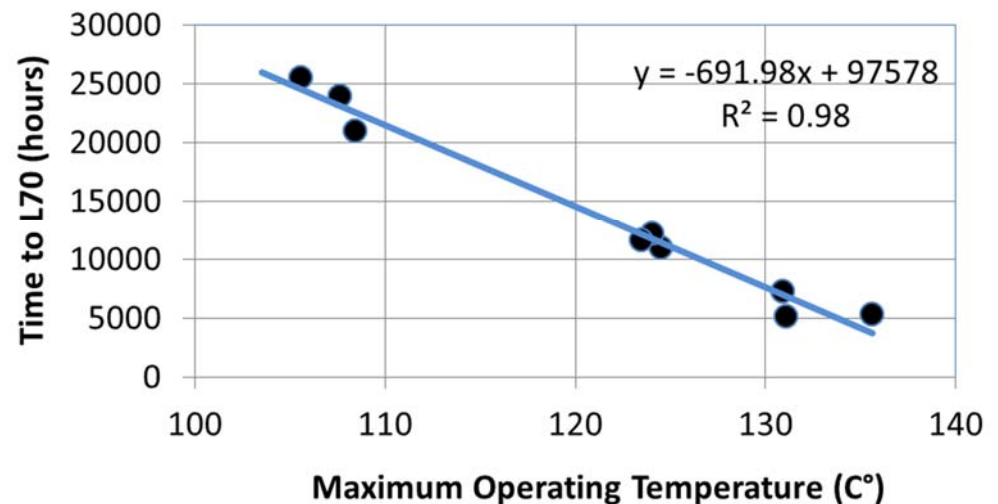
For the product tested:

- Time to failure, projected L70 as a function of maximum operating temperature, shows an inverse linear relationship
 - Goodness-of-fit (R^2) > 0.9
- The projected L70 values are similar for each delta T condition
 - Cycling has minimum effect

Maximum operating temperature (°C)

Delta T	Dwell time		
	2 hrs	4 hrs	Continuous on
80°C	106°C	108°C	108°C
90 °C	125°C	124°C	124°C
100°C	131°C	136°C	131°C

LED A-Lamp



Time to failure (L70 in hours)

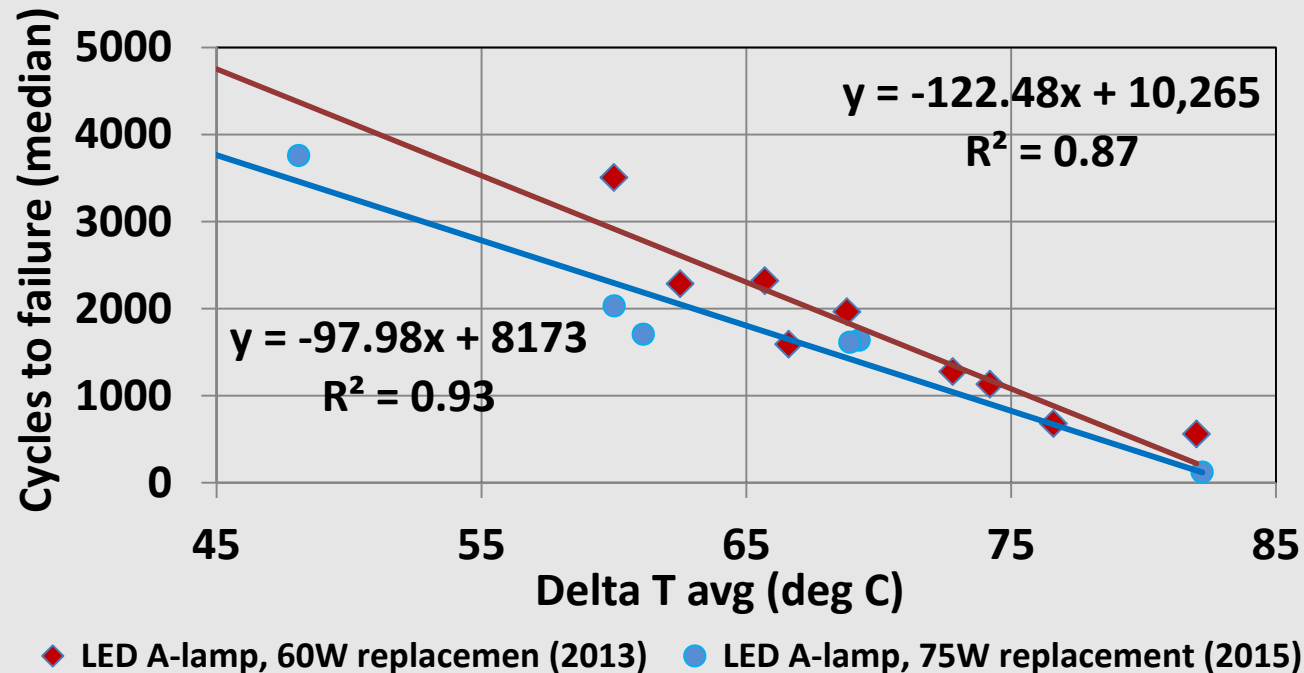
Delta T	Dwell time		
	2 hrs	4 hrs	Continuous on
80°C	25,528	20,998	23,979
90 °C	11,019	12,185	11,657
100°C	7,289	5,308	5,171

Results: A-lamp

- Study results show for the LED A-lamps tested
 - Both failure types exist
 - Catastrophic
 - ON-OFF cycling (dynamic stress) influenced catastrophic failure
 - Parametric
 - Maximum operating temperature influenced lumen depreciation
- Shorter of the two determines the lifetime of the system in a given application
 - Catastrophic failure time is shorter than lumen depreciation, L70
 - Strong case for including switching ON and OFF into test methods
- Contrary to conventional wisdom, switching LED systems on and off can shorten lamp life.

Results: A-lamp

- Results from two LED A-lamp life tests
 - The 60W equivalent product was procured in 2013
 - The 75W equivalent product was procured in 2015



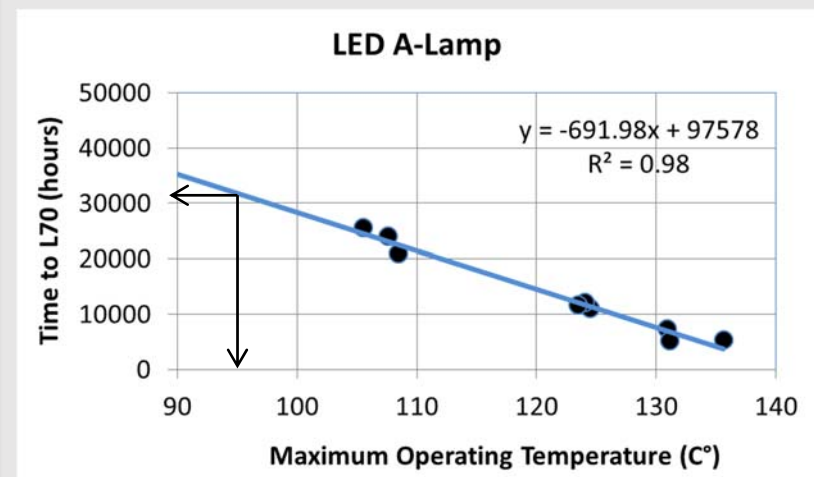
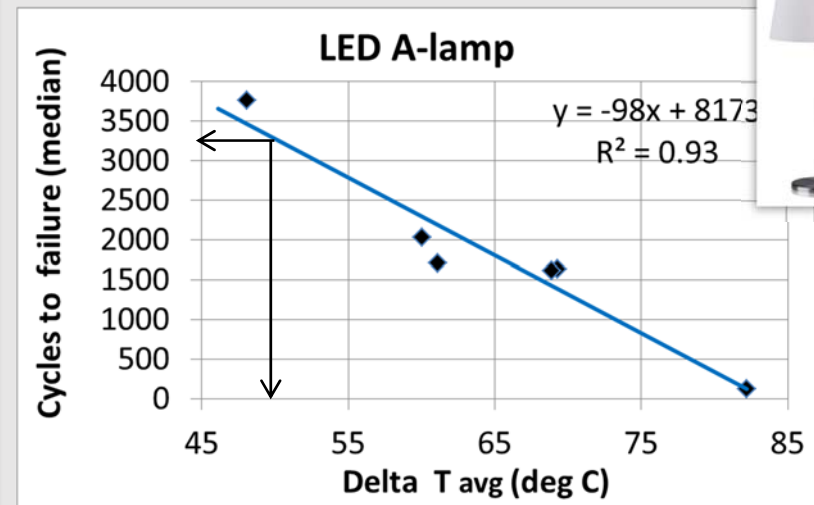
Usefulness of test method

LED A-lamp life estimation in an application

- To illustrate the usefulness of this test method and results, two applications where the same lamp can be used were selected and their lamp life in each application was estimated.

Example 1: LED Table lamp

- Used 3 hours per day
 - Maximum $T_j = 95^\circ\text{C}$ at $T_{\text{room}} 30^\circ\text{C}$
 - $\Delta T_{\text{avg}} = T_{\text{avg}} - T_{\text{room}} = 50^\circ\text{C}$
- Estimated median lamp life
 - Catastrophic : 3250 cycles = 8.9 yrs
 - L70: 32,000 hrs = 29 yrs
- Lamp life = 8.9 years



LED A-lamp life estimation in applications

- The tested LED A-lamp
 - In a table lamp will last 8.9 years
 - In a non-IC downlight will last 1.9 years



Table lamp



Non-IC downlight

Summary

- Failure types include both catastrophic and parametric.
- Contrary to conventional wisdom, switching LED systems on and off can shorten lamp life.
- Cycles-to-failure (catastrophic) has a high correlation to time-averaged delta temperature.
- Time-to-L70 (parametric failure) has a high correlation to maximum operating temperature.
- The proposed test method can help predict LED system life in any application if T_j and use pattern (ON-OFF cycling) are known.
- For more information:

Narendran, N., Y. Liu, X. Mou, D.R. Thotagamuwa, and O.V. Madihe Eshwarage. 2016. [Projecting LED product life based on application](http://www.lrc.rpi.edu/programs/solidstate/pdf/Narendran-SPIE2016-99540G.pdf). *Proceedings of SPIE* 9954, Fifteenth International Conference on Solid State Lighting and LED-based Illumination Systems, 99540G (September 14, 2016); doi: 10.1117/12.2240464.

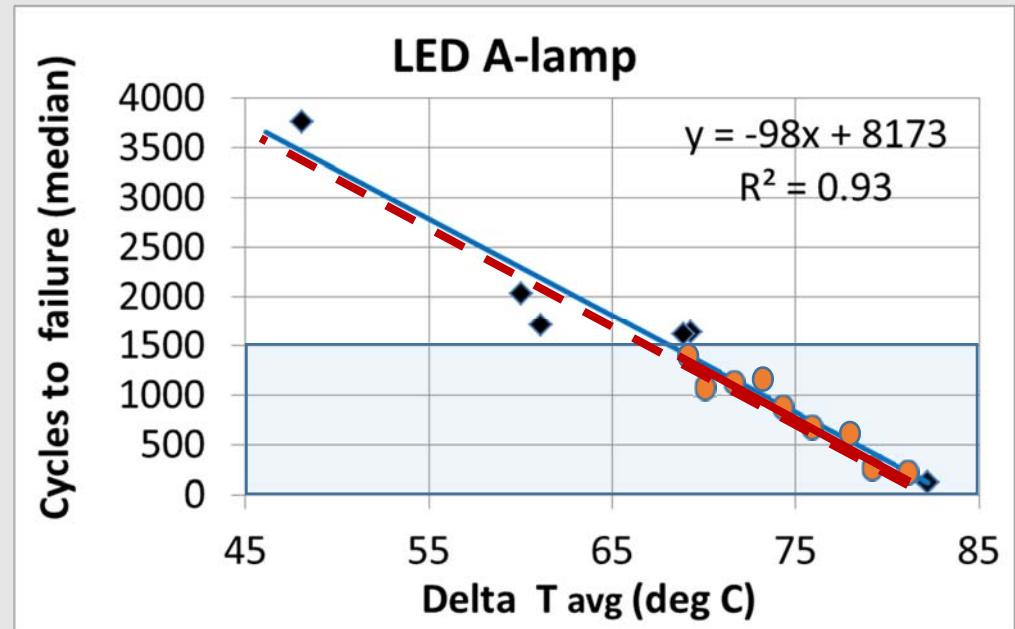
<http://www.lrc.rpi.edu/programs/solidstate/pdf/Narendran-SPIE2016-99540G.pdf>



Final thought

Duration of life testing

- By selecting suitable DT and dwell time, the cycles to failure can be restricted to within 1500.
 - Time to failure within 3000 hours
 - Data extrapolation can be used to determine cycles to failure at lower temperatures
- Test time can be 3000 hours or less.



Acknowledgments

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Thank you



www.lrc.rpi.edu/programs/solidstate/index.asp